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(54) Method for evaluating offset
of point of impact of projectile in
gun trainer or simulator

(57) The method evaluates the vertical offset ΔH of the simulated point of impact (X) of the projectile with respect to a target (Z) onto which a sight is aligned, and displays the offset according to the function $\Delta H = k_1 \cdot k_2 \cdot \Delta E$, where k_1 is a factor dependent on the type of ammunition, k_2 is a factor dependent on

momentary target range and ΔE is a value corresponding to the range error. The range error is determined by calculating the intersection of the projectile trajectory (F) with the line of sight (V).

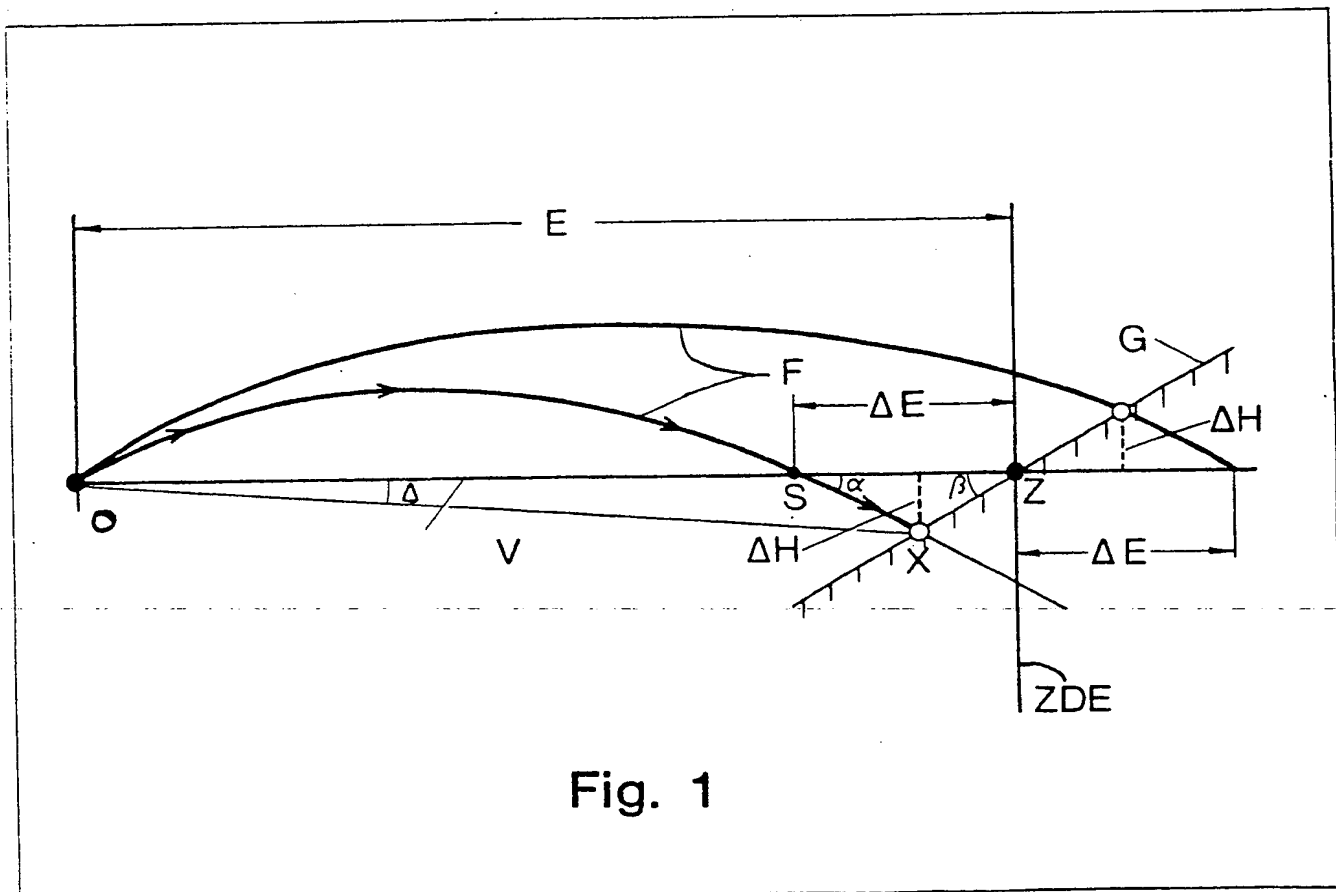


Fig. 1



Fig. 1

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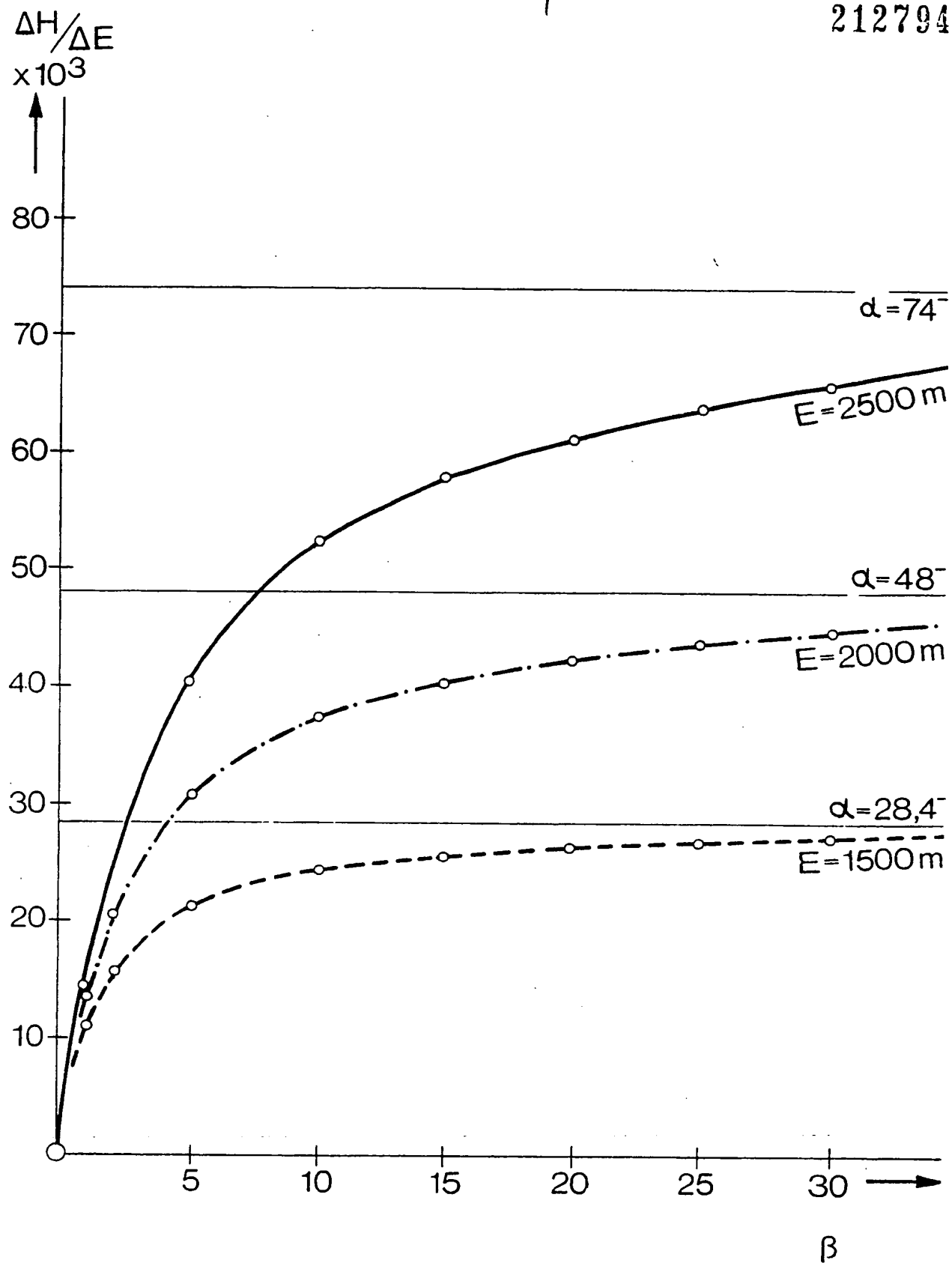


Fig. 2

projectile with respect to a target onto which a sight is aligned, wherein the vertical offset of the simulated point of impact (X) of the projectile relative to the target (Z) is displayed according to the function $\Delta H = k_1 \cdot k_2 \cdot \Delta E$ where

- 5 ΔH = vertical offset, 5
 k_1 = factor, dependent on type of ammunition,
 k_2 = factor, dependent on momentary target range,
 ΔE = range error.
- 10 2. Method according to Claim 1, wherein the range error ΔE is determined by calculating 10
 the intersection of the projectile trajectory (F) with the line of sight (V).
 3. A gun trainer or simulator method substantially as herein described.

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